

Fig. 1: Thinning strategy

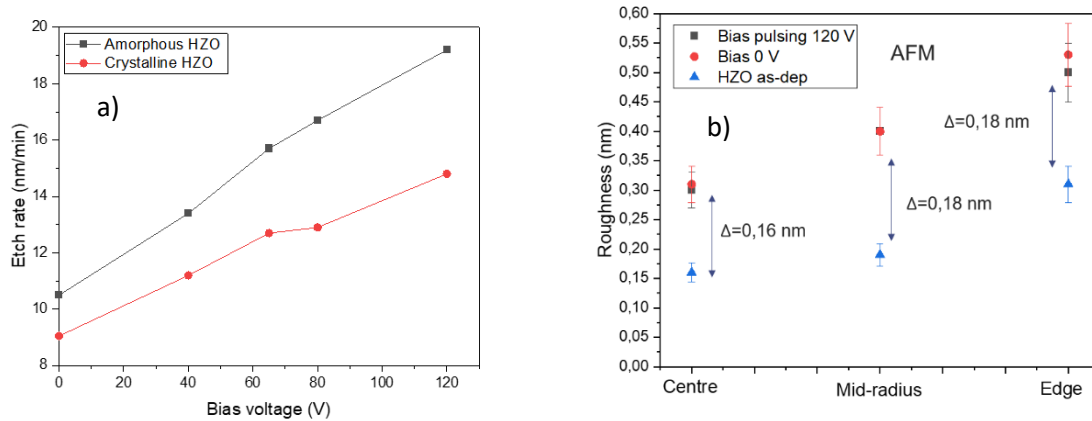


Fig. 2: (a) HZO etch rate as a function of bias voltage, (b) AFM results

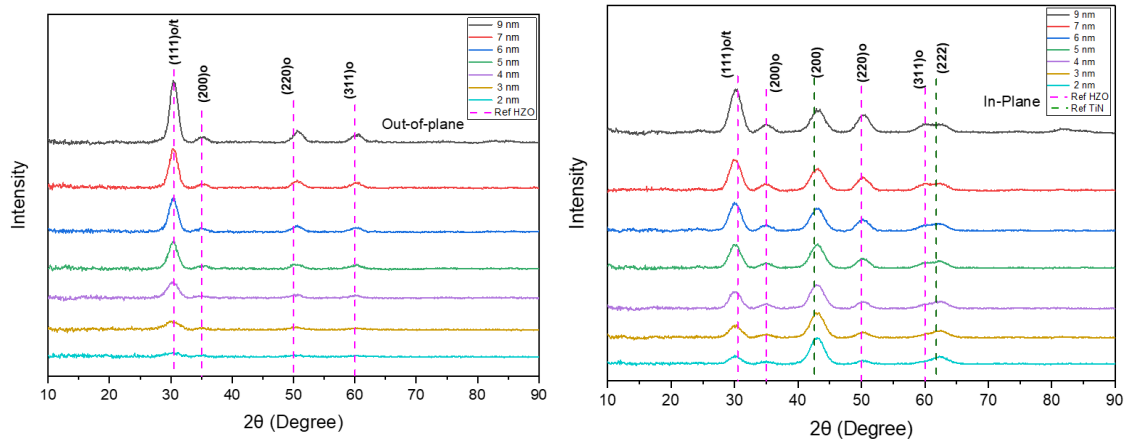


Fig. 3: Out-of-plane and In-plane XRD spectra measured on 10nm crystalline HZO along thinning process